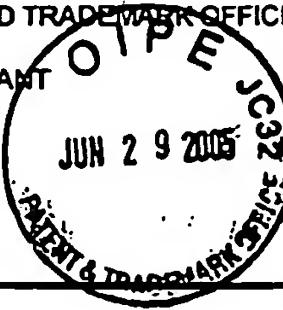


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2416		SERIAL NO. 10/688,439	
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT: Trung Tri Doan et al.			
					FILING DATE October 16, 2003		GROUP 2813	
U.S. PATENT DOCUMENTS								
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>DS</i>	AM	6,013,583	01/2000	Ajmera et al.				
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
<i>DS</i>	AM	0817251 A1	11.06.97	EPO (IBM)			Yes	No
<i>DS</i>	AK	US2004/021156	07.07.03	PCT (Micron - Internat'l Search Rep.)				
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>DS</i>	AM	Chen et al., <i>Excimer Laser-Induced Ti Silicidation to Eliminate the Fine-Line Effect for Integrated Circuit Device Fabrication</i> , J. ELECTROCHEM. SOC., Vol. 149, No. 11, pp. G609-G612 (2002).						
<i>DS</i>	AN	Nishiyama et al., <i>Agglomeration Resistant Self-Aligned Silicide Process Using N₂ Implantation Into TiSi₂</i> , JPN. J. APPL. PHYS., Vol. 36, Pt. 1, No. 6A, pp. 3639-3643 (June 1997).						
<i>DS</i>	AO	Wolf, <i>Chapter 13: Polycides and Salicides of TiSix, CoSi₂, and NiSi, SILICON PROCESSING FOR THE VLSI ERA</i> , Vol. IV, pp. 603-604 (pre-2003).						
EXAMINER		DATE CONSIDERED		<i>RS</i> 7/19/05				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2416	SERIAL NO. 10/688,439		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT: Trung Tri Doan et al.					
		JUN 29 2005 U.S. PATENT & TRADEMARK OFFICE		FILING DATE October 16, 2003	GROUP 2813		
U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DS	AA	2001/0041250 A1	11/2001	Werkhoven et al.			
	AB	2002/0000195 A1	01/2002	Bang et al.			
	AC	2002/0018849 A1	02/2002	George et al.			
	AD	2003/0032281 A1	02/2003	Werkhoven et al.			
	AE	2003/0129826 A1	07/2003	Werkhoven et al.			
	AF	2004/0209484 A1	10/2004	Hill et al.			
✓	AG	2004/0266153 A1	12/2004	Hu			
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AJ						Yes
	AK						No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AM						
	AN						
	AO						
EXAMINER		DATE CONSIDERED		7/19/05			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							